

# 1-Mbit (128 K × 8) Static RAM

#### **Features**

- Pin- and function-compatible with CY7C1018CV33 and CY7C1019CV33
- High speed
  □ t<sub>AA</sub> = 10 ns
- Low Active Power
  □ I<sub>CC</sub> = 60 mA @ 10 ns
- Low CMOS Standby Power
  □ I<sub>SB2</sub> = 3 mA
- 2.0 V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Center power/ground pinout
- Easy memory expansion with CE and OE options
- Available in Pb-free 32-pin 400-Mil wide Molded SOJ, 32-pin TSOP II and 48-ball VFBGA packages

#### **Functional Description**

The CY7C1018DV33/CY7C1019DV33 is a high-performance CMOS static RAM organized as 131,072 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable  $(\overline{CE})$ , an active LOW Output Enable  $(\overline{OE})$ , and three-state drivers. This device has an automatic power-down feature that significantly reduces power consumption when deselected.

Writing to the device is accomplished by taking Chip Enable  $(\overline{CE})$  and Write Enable  $(\overline{WE})$  inputs LOW. Data on the eight I/O pins  $(I/O_0$  through  $I/O_7)$  is then written into the location specified on the address pins  $(A_0$  through  $A_{16}$ ).

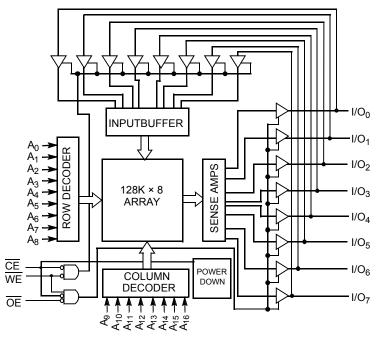
Reading from the device is accomplished by taking Chip Enable (CE) and Output Enable (OE) LOW while forcing Write Enable (WE) HIGH. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins (I/O<sub>0</sub> through I/O<sub>7</sub>) are <u>placed</u> in a high-impedance state when the device is deselected (CE HIGH), the outputs are <u>disabled</u> ( $\overline{OE}$  HIGH), or during a write operation ( $\overline{CE}$  LOW, and  $\overline{WE}$  LOW).

The CY7C1018DV33/CY7C1019DV33 are available in Pb-free 32-pin 400-Mil wide Molded SOJ, 32-pin TSOP II and 48-ball VFBGA packages.

For a complete list of related documentation, click here.

## **Logic Block Diagram**





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#### **Selection Guide**

Description	-10 (Industrial)	Unit
Maximum Access Time	10	ns
Maximum Operating Current	60	mA
Maximum Standby Current	3	mA

## **Pin Configurations**

Figure 1. 48-ball VFBGA pinout (Top View) [1]

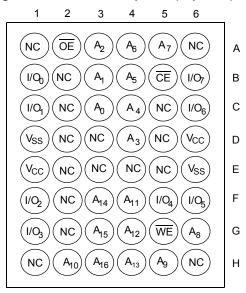
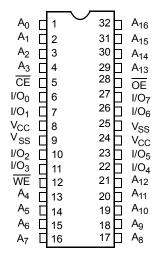


Figure 2. 32-pin SOJ / TSOP II pinout (Top View)



#### Note

<sup>1.</sup> NC pins are not connected on the die.



### **Maximum Ratings**

DC Input Voltage [2]	0.3 V to V <sub>CC</sub> + 0.3 V
Current into Outputs (LOW)	20 mA
Static Discharge Voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch-up Current	> 200 mA

## **Operating Range**

Range	<b>Ambient Temperature</b>	V <sub>cc</sub>	Speed
Industrial	–40 °C to +85 °C	$3.3~V\pm0.3~V$	10 ns

#### **Electrical Characteristics**

Over the Operating Range

D	Description	Total Considiations		-10 (Inc	dustrial)	I I m ! 4
Parameter	Description	lest Conditions	Test Conditions		Max	Unit
V <sub>OH</sub>	Output HIGH voltage	Min $V_{CC}$ , $I_{OH} = -4.0 \text{ mA}$	Min $V_{CC}$ , $I_{OH} = -4.0 \text{ mA}$			V
V <sub>OL</sub>	Output LOW voltage	Min V <sub>CC</sub> , I <sub>OL</sub> = 8.0 mA		-	0.4	V
V <sub>IH</sub>	Input HIGH voltage			2.0	V <sub>CC</sub> + 0.3	V
V <sub>IL</sub>	Input LOW voltage [2]			-0.3	0.8	V
I <sub>IX</sub>	Input leakage current	$GND \le V_{IN} \le V_{CC}$		<b>–</b> 1	+1	μΑ
I <sub>OZ</sub>	Output leakage current	$GND \le V_{IN} \le V_{CC}$ , output disabled		<b>–</b> 1	+1	μΑ
I <sub>CC</sub>	V <sub>CC</sub> operating supply current	V <sub>CC</sub> = Max, I <sub>OUT</sub> = 0 mA,	100 MHz	-	60	mA
		$f = f_{MAX} = 1/t_{RC}$	83 MHz	-	55	mA
			66 MHz	-	45	mA
			40 MHz	-	30	mA
I <sub>SB1</sub>	Automatic CE power-down current – TTL inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{ f = f}_{\text{MAX}} \end{aligned}$		_	10	mA
I <sub>SB2</sub>	Automatic CE power-down current – CMOS inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V or V}_{\text{IN}} \leq 0.3 \text{ V}, \text{f} = \end{aligned}$	0	I	3	mA

Document Number: 38-05481 Rev. \*J

<sup>2.</sup>  $V_{IL(min)}$  = -2.0 V and  $V_{IH(max)}$  =  $V_{CC}$  + 1 V for pulse durations of less than 5 ns.



## Capacitance

Parameter [3]	Description	Description Test Conditions			
C <sub>IN</sub>	Input Capacitance T <sub>A</sub> = 25 °C, f = 1 MHz, V <sub>CC</sub> = 3.3 V		8	pF	
C <sub>OUT</sub>	Output Capacitance		8	pF	

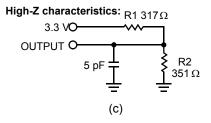
#### **Thermal Resistance**

Parameter	Description	Test Conditions	32-pin SOJ	32-pin TSOP II	48-ball VFBGA	Unit
$\Theta_{JA}$		Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit		62.22	36	°C/W
$\Theta_{\sf JC}$	Thermal Resistance (Junction to Case)	board	38.14	21.43	9	°C/W

### **AC Test Loads and Waveforms**

Figure 3. AC Test Loads and Waveforms [4]





#### Notes

- Tested initially and after any design or process changes that may affect these parameters.
- 4. AC characteristics (except High Z) are tested using the load conditions shown in Figure 3 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 3 (c).



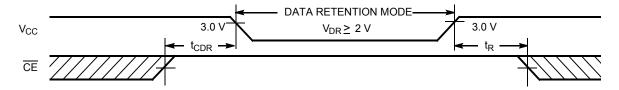
### **Data Retention Characteristics**

Over the Operating Range

Parameter	Description	Conditions	Min	Max	Unit
V <sub>DR</sub>	V <sub>CC</sub> for data retention		2.0	_	V
I <sub>CCDR</sub>	Data retention current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	_	3	mA
t <sub>CDR</sub> <sup>[5]</sup>	Chip deselect to data retention time		0	_	ns
t <sub>R</sub> <sup>[6]</sup>	Operation recovery time		t <sub>RC</sub>	_	ns

#### **Data Retention Waveform**

Figure 4. Data Retention Waveform



- 5. Tested initially and after any design or process changes that may affect these parameters.
   6. Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min.)</sub> ≥ 50 μs or stable at V<sub>CC(min.)</sub> ≥ 50 μs.



## **Switching Characteristics**

Over the Operating Range

Parameter [7]	Description	-10 (Inc	lustrial)	11!4
Parameter 111	Description	Min	Max	Unit
Read Cycle		•		_
t <sub>power</sub> <sup>[8]</sup>	V <sub>CC</sub> (typical) to the first access	100	_	μS
t <sub>RC</sub>	Read cycle time	10	_	ns
t <sub>AA</sub>	Address to data valid	_	10	ns
t <sub>OHA</sub>	Data hold from address change	3	_	ns
t <sub>ACE</sub>	CE LOW to data valid	_	10	ns
t <sub>DOE</sub>	OE LOW to data valid	_	5	ns
t <sub>LZOE</sub>	OE LOW to low Z [9]	0	_	ns
t <sub>HZOE</sub>	OE HIGH to high Z [9, 10]	_	5	ns
t <sub>LZCE</sub>	CE LOW to low Z [9]	3	_	ns
t <sub>HZCE</sub>	CE HIGH to high Z [9, 10]	_	5	ns
t <sub>PU</sub> <sup>[11]</sup>	CE LOW to power-up	0	_	ns
t <sub>PD</sub> <sup>[11]</sup>	CE HIGH to power-down	_	10	ns
Write Cycle [12	, 13]			
t <sub>WC</sub>	Write cycle time	10	-	ns
t <sub>SCE</sub>	CE LOW to write end	8	_	ns
t <sub>AW</sub>	Address set-up to write end	8	_	ns
t <sub>HA</sub>	Address hold from write end	0	_	ns
t <sub>SA</sub>	Address set-up to write start	0	_	ns
t <sub>PWE</sub>	WE pulse width	7	_	ns
t <sub>SD</sub>	Data set-up to write end	5	_	ns
t <sub>HD</sub>	Data hold from write end	0	_	ns
t <sub>LZWE</sub>	WE HIGH to low Z [9]	3	_	ns
t <sub>HZWE</sub>	WE LOW to high Z [9, 10]	_	5	ns

- 7. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.

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- 12. The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. CE and WE must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

  13. The minimum write cycle time for Write Cycle no. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



## **Switching Waveforms**

Figure 5. Read Cycle No. 1 (Address Transition Controlled) [14, 15]

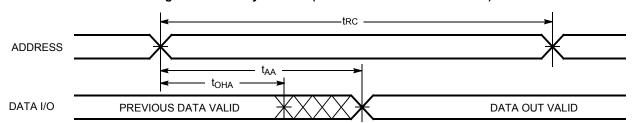
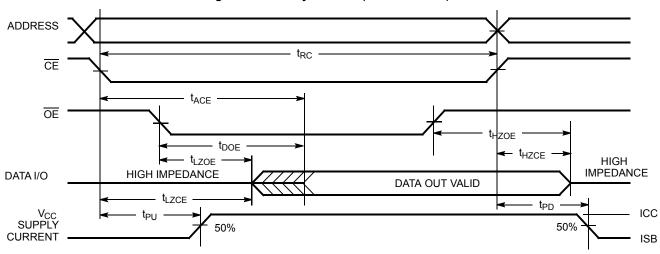


Figure 6. Read Cycle No. 2 ( $\overline{\text{OE}}$  Controlled) [15, 16]



#### Notes

<sup>14. &</sup>lt;u>Dev</u>ice is continuously selected. OE, CE = V<sub>IL</sub>.

15. WE is HIGH for Read cycle.

16. Address valid prior to or coincident with CE transition LOW.



## Switching Waveforms (continued)

Figure 7. Write Cycle No. 1 (CE Controlled) [17, 18]

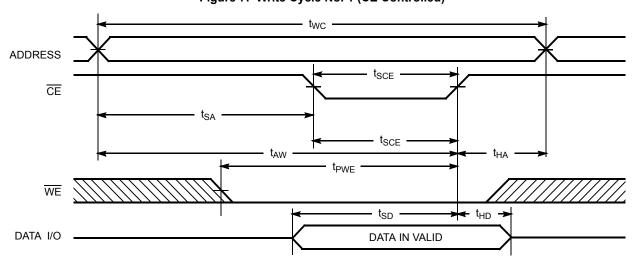
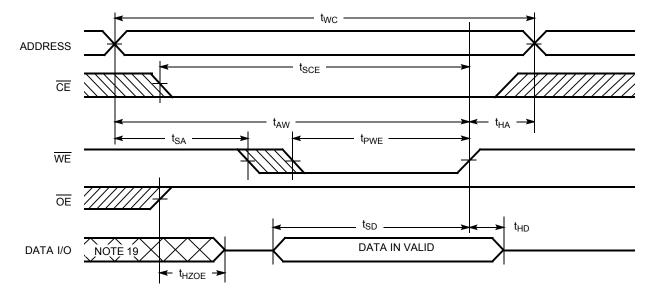


Figure 8. Write Cycle No. 2 (WE Controlled, OE HIGH During Write) [17, 18]



#### Notes

<sup>17.</sup> Data I/O is high impedance if  $\overline{OE} = V_{IJ}$ .

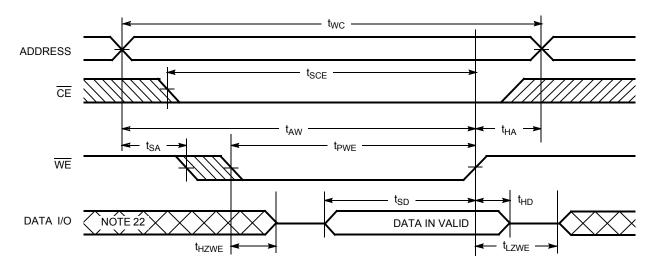
18. If  $\overline{CE}$  goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

<sup>19.</sup> During this period the I/Os are in the output state and input signals should not be applied.



## Switching Waveforms (continued)

Figure 9. Write Cycle No. 3 (WE Controlled, OE LOW) [20, 21]



<sup>20.</sup> If CE goes HIGH simultaneously with WE going HIGH, the <u>output</u> remains in a high-impedance state.

21. The minimum write cycle time for Write Cycle no. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

22. During this period the I/Os are in the output state and input signals should not be applied.



## **Truth Table**

CE	OE	WE	I/O <sub>0</sub> –I/O <sub>7</sub>	Mode	Power
Н	Х	Х	High Z	Power-Down	Standby (I <sub>SB</sub> )
L	L	Н	Data Out	Read	Active (I <sub>CC</sub> )
L	Х	L	Data In	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I <sub>CC</sub> )

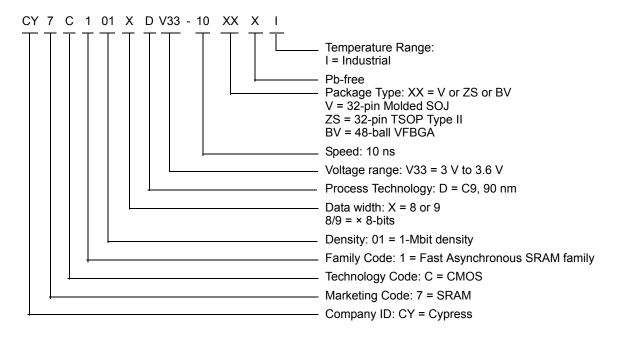


## **Ordering Information**

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1018DV33-10VXI	51-85041	32-pin (300-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1019DV33-10VXI	51-85033	32-pin (400-Mil) Molded SOJ (Pb-free)	
	CY7C1019DV33-10ZSXI	51-85095	32-pin TSOP Type II (Pb-free)	
	CY7C1019DV33-10BVXI	51-85150	48-ball VFBGA (Pb-free)	

Please contact your local Cypress sales representative for availability of these parts.

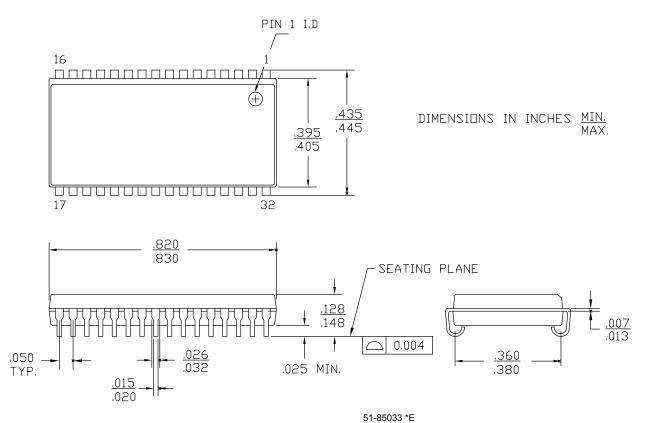
#### **Ordering Code Definitions**





## **Package Diagrams**

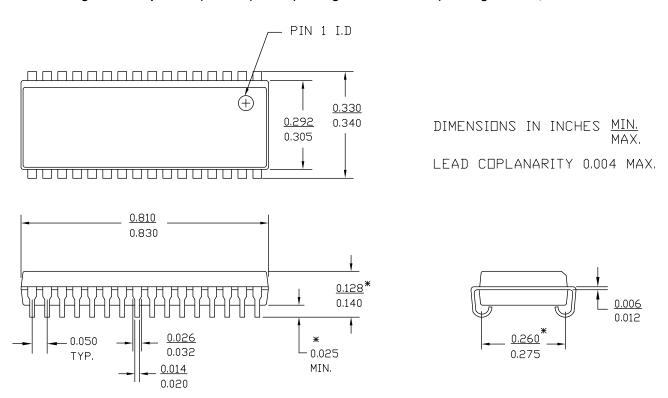
Figure 10. 32-pin SOJ (400 Mils) V32.4 (Molded SOJ V33) Package Outline, 51-85033





## Package Diagrams (continued)

Figure 11. 32-pin SOJ (300 Mils) V32.3 (Catalog 32.3 Molded SOJ) Package Outline, 51-85041

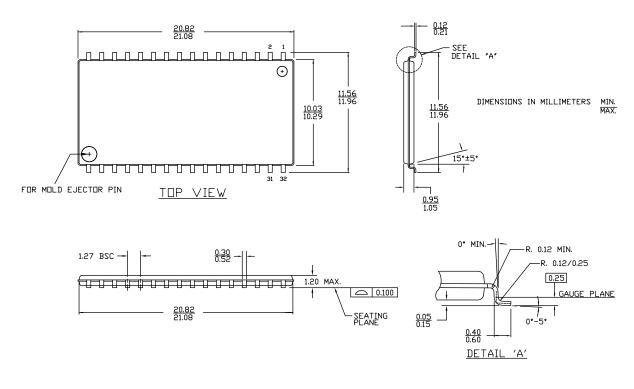


51-85041 \*D



## Package Diagrams (continued)

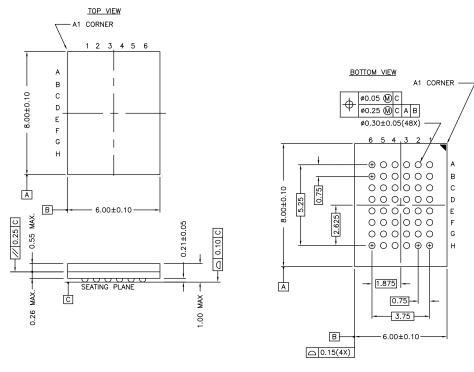
Figure 12. 32-pin TSOP II (20.95 × 11.76 × 1.0 mm) ZS32 Package Outline, 51-85095





## Package Diagrams (continued)

Figure 13. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150



NOTE:
PACKAGE WEIGHT: See Cypress Package Material Declaration Datasheet (PMDD) posted on the Cypress web.

51-85150 \*H



## **Acronyms**

Acronym	Description					
CE	Chip Enable					
CMOS	Complementary Metal Oxide Semiconductor					
I/O	Input/Output					
ŌĒ	Output Enable					
SOJ	Small Outline J-lead					
SRAM	Static Random Access Memory					
TSOP	Thin Small Outline Package					
TTL	Transistor-Transistor Logic					
VFBGA	Very Fine-Pitch Ball Grid Array					
WE	Write Enable					

## **Document Conventions**

#### **Units of Measure**

Symbol	Unit of Measure				
°C	degree Celsius				
MHz	megahertz				
μΑ	microampere				
μS	microsecond				
mA	milliampere				
mm	millimeter				
ns	nanosecond				
Ω	ohm				
%	percent				
pF	picofarad				
V	volt				
W	watt				



## **Document History Page**

Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change
**	201560	See ECN	SWI	Advance Information data sheet for C9 IPP
*A	233750	See ECN	RKF	Updated Electrical Characteristics: DC parameters modified as per EROS (Spec # 01-02165 Rev *A) Updated Ordering Information: Added Pb-free offering.
*B	262950	See ECN	RKF	Added Data Retention Characteristics. Updated Switching Characteristics: Added T <sub>power</sub> parameter and its details. Updated Ordering Information: Shaded all Pb-free MPNs.
*C	307598	See ECN	RKF	Removed 12 ns speed bin and 15 ns speed bin related information in all instances across the document.
*D	520652	See ECN	VKN	Changed status from Preliminary to Final. Removed Commercial Temperature Range related information in all instances across the document. Removed 8 ns speed bin related information in all instances across the document. Added 48-ball VFBGA package related information in all instances across the document. Updated Electrical Characteristics: Added values of I <sub>CC</sub> parameter (for frequencies 83 MHz, 66 MHz and 40 MHz) Updated Note 2 (Replaced "V <sub>IH(max)</sub> = V <sub>CC</sub> + 2 V" with "V <sub>IH(max)</sub> = V <sub>CC</sub> + 1 V") Updated Thermal Resistance. Updated Ordering Information. Updated Package Diagrams: Added Figure 13 (spec 51-85150).
*E	3110052	12/14/2010	AJU	Added Ordering Code Definitions. Updated Package Diagrams.
*F	3416342	10/20/2011	TAVA	Updated Functional Description (Removed the Note "For guidelines on SRAM system design, please refer to the 'System Design Guidelines' Cypress application note, available on the internet at www.cypress.com link." and its reference in Functional Description). Updated Electrical Characteristics. Updated Switching Waveforms. Updated Package Diagrams. Added Acronyms and Units of Measure. Updated to new template.
*G	4324792	03/28/2014	VINI	Added CY7C1018DV33 related information across the document. Updated Ordering Information (Updated part numbers). Updated Package Diagrams: spec 51-85033 – Changed revision from *D to *E. spec 51-85150 – Changed revision from *G to *H. Updated to new template.
*H	4531367	10/10/2014	NILE	Updated Ordering Information: Replaced "51-85033" with "51-85041" in "Package Diagram" column for CY7C1018DV33-10VXI. Updated Package Diagrams: Added Figure 11 (spec 51-85041).



## **Document History Page** (continued)

	Document Title: CY7C1018DV33/CY7C1019DV33, 1-Mbit (128 K × 8) Static RAM Document Number: 38-05481							
Rev.	ECN No.	Issue Date	Orig. of Change	Description of Change				
*	4574311	11/19/2014	NILE	Updated Functional Description: Added "For a complete list of related documentation, click here." at the end. Updated Package Diagrams: spec 51-85041 – Changed revision from *C to *D.				
*J	4777177	05/26/2015	NILE	Updated Package Diagrams: spec 51-85095 – Changed revision from *B to *D. Updated to new template.				



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